	Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137	OIPA
	Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Hisashi Ohtani		
			Filing Date September 9, 2003	Group Art Unit 2822	MAY 1 2 2005
- 1	(37 CFR §1.98(b))		Depterment 1, 2000		

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Examiner Signature	Date Considered 6-8-05
EXAMINER: Initial dilation considered. Draw line through citation if next communication to applicant.	
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137 OIPE
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WILL III. OWNIT	$(\alpha \circ c)$
EXAMINER: latters citation considered. Draw line through citation	not in conformance and not considered. Include copy of this form with
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